### Description

SUPERFET II MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. Consequently, SUPERFET II MOSFET Easy drive series helps manage EMI issues and allows for easier design implementation.

#### Features

- 650 V @ T<sub>J</sub> = 150°C
- Typ.  $R_{DS(on)} = 220 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q<sub>g</sub> = 48 nC)
- Low Effective Output Capacitance (Typ. C<sub>oss(</sub>eff.) = 129 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

### Applications

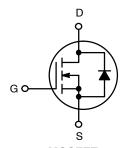
- Computing / Display Power Supplies
- Telecom / Server Power Supplies
- Industrial Power Supplies
- Lighting / Charger / Adapter



### **ON Semiconductor®**

### www.onsemi.com

V <sub>DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX	
600 V	260 mΩ @ 10 V	15 A	

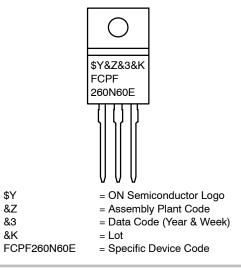






TO-220F Ultra Narrow Lead CASE 221BN

### MARKING DIAGRAM



### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 2 of this data sheet.

Symbol	Paramet	Value	Unit V		
V <sub>DSS</sub>	Drain to Source Voltage			600	
V <sub>GSS</sub>	Gate to Source Voltage	– DC	±20	V	
		– AC (f > 1 Hz)	±30		
Ι <sub>D</sub>	Drain Current	– Continuous (T <sub>C</sub> = 25°C)	15*	А	
		– Continuous (T <sub>C</sub> = 100°C)	9.5*		
I <sub>DM</sub>	Drain Current	- Pulsed (Note 1)	45*	А	
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		292.5	mJ	
I <sub>AS</sub>	Avalanche Current (Note 2)		3.0	А	
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		1.56	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		20	V/ns	
	MOSFET dv/dt	100			
PD	Power Dissipation	(T <sub>C</sub> = 25°C)	36	W	
		– Derate Above 25°C	0.29	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		–55 to +150	°C	
ΤL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300	°C	

### **MOSFET MAXIMUM RATINGS** (T<sub>C</sub> = 25°C, Unless otherwise noted)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality stresses exceeding those listed in the Maximum Hatings table may damage t should not be assumed, damage may occur and reliability may be affected. \*Drain current limited by maximum junction temperature. 1. Repetitive rating: pulse width limited by maximum junction temperature. 2.  $I_{AS} = 3 \text{ A}$ ,  $V_{DD} = 50 \text{ V}$ ,  $R_G = 25 \Omega$ , starting  $T_J = 25^{\circ}\text{C}$ . 3.  $I_{SD} \leq 7.5 \text{ A}$ , di/dt  $\leq 200 \text{ A}/\mu\text{s}$ ,  $V_{DD} \leq \text{BV}_{DSS}$ , starting  $T_J = 25^{\circ}\text{C}$ .

### THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{ extsf{ heta}JC}$	Thermal Resistance, Junction to Case, Max.	3.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	°C/W

#### PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Shipping
FCPF260N60E-F154	FCPF260N60E	TO-220F (Pb-Free)	50 Units / Tube

### **ELECTRICAL CHARACTERISTICS** ( $T_C = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
OFF CHARACT	ERISTICS					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$V_{GS}$ = 0 V, I <sub>D</sub> = 10 mA, T <sub>J</sub> = 25 °C	600	-	-	V
		$V_{GS}$ = 0 V, I <sub>D</sub> = 10 mA, T <sub>J</sub> = 150°C	650	-	-	V
$\Delta \text{BV}_{\text{DSS}}  /  \Delta \text{T}_{\text{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = 10 \text{ mA}$ , Referenced to $25^{\circ}\text{C}$	-	0.67	_	V/°C
BV <sub>DS</sub>	Drain-Source Avalanche Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 15 A	-	700	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 480 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-	-	1.0	μA
		$V_{DS}$ = 480 V, $T_{C}$ = 125°C	-	2.6	-	
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS}$ = ±20 V, $V_{DS}$ = 0 V		-	±100	nA
ON CHARACTE	RISTICS	-	-			
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 250 \ \mu A$	2.5	-	3.5	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 7.5 A	-	0.22	0.26	Ω
<b>9</b> FS	Forward Transconductance	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 7.5 A	-	15.5	-	S
OYNAMIC CHA	RACTERISTICS	·				
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$	-	1880	2500	pF
C <sub>oss</sub>	Output Capacitance	1	-	1330	1770	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1	-	85	130	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 380 \text{ V}, V_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$	-	32	-	pF
C <sub>oss(eff.)</sub>	Effective Output Capacitance	$V_{DS}$ = 0 V to 480 V, $V_{GS}$ = 0 V	-	129	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10 V	$V_{DS} = 380 \text{ V}, \text{ I}_{D} = 7.5 \text{ A}, \text{ V}_{GS} = 10 \text{ V}$	-	48	62	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	(Note 4)	-	7.4	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	1	_	17	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	5.8	-	Ω
WITCHING CH	IARACTERISTICS	•				
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD}$ = 380 V, I <sub>D</sub> = 7.5 A, V <sub>GS</sub> = 10 V,	_	20	50	ns
t <sub>r</sub>	Turn-On Rise Time	R <sub>g</sub> = 4.7 Ω (Note 4)	-	11	32	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	1`´´	_	89	188	ns
t <sub>f</sub>	Turn-Off Fall Time		_	13	36	ns
	N DIODE CHARACTERISTICS	•				
IS	Maximum Continuous Source to Drain Diode Forward Current		_	-	15	Α
I <sub>SM</sub>	Maximum Pulsed Source to Drain Diode Forward Current		-	-	45	А
V <sub>SD</sub>	Source to Drain Diode Forward Voltage	$V_{GS} = 0 V, I_{SD} = 7.5 A$	_	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>DD</sub> = 400 V, I <sub>SD</sub> = 7.5 A,	_	270	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	- dl <sub>F</sub> /dt = 100 A/µs		3.6	_	μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially independent of operating temperature typical characteristics.

Q<sub>rr</sub>

### **TYPICAL PERFORMANCE CHARACTERISTICS**

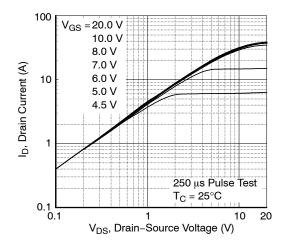
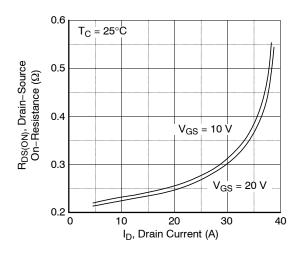
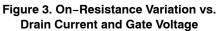


Figure 1. On-Region Characteristics





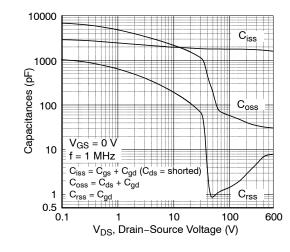


Figure 5. Capacitance Characteristics

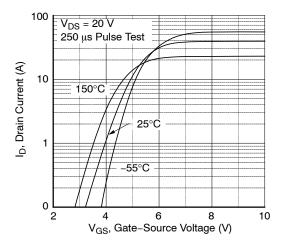


Figure 2. Transfer Characteristics

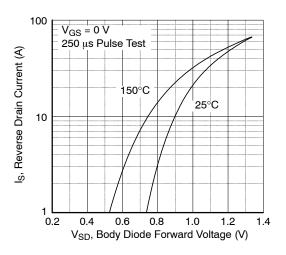


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

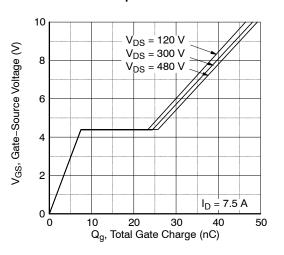
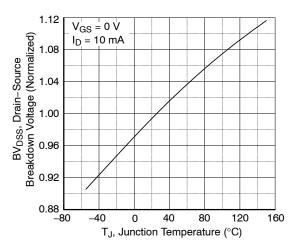


Figure 6. Gate Charge Characteristics

### TYPICAL PERFORMANCE CHARACTERISTICS (continued)





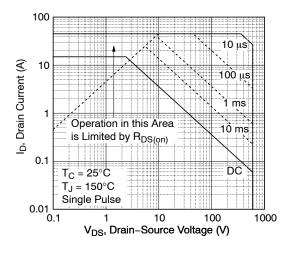


Figure 9. Maximum Safe Operating Area

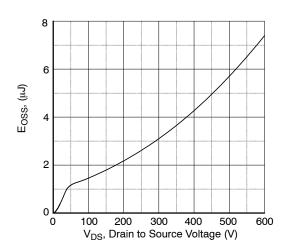


Figure 11. E<sub>OSS</sub> vs. Drain-to-Source Voltage

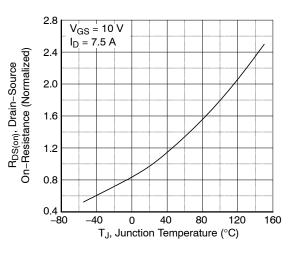


Figure 8. On–Resistance Variation vs. Temperature

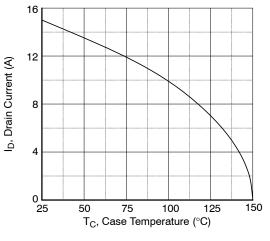


Figure 10. Maximum Drain Current vs. Case Temperature

### TYPICAL PERFORMANCE CHARACTERISTICS (continued)

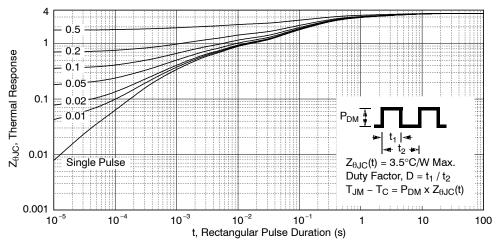


Figure 12. Transient Thermal Response Curve

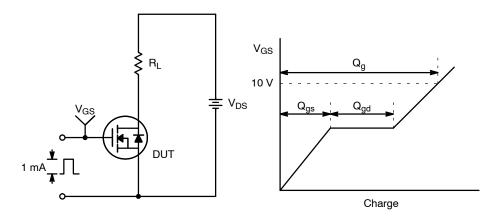


Figure 13. Gate Charge Test Circuit & Waveform

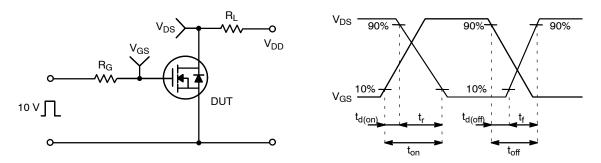


Figure 14. Resistive Switching Test Circuit & Waveforms

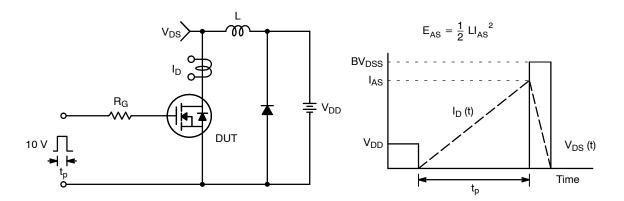


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

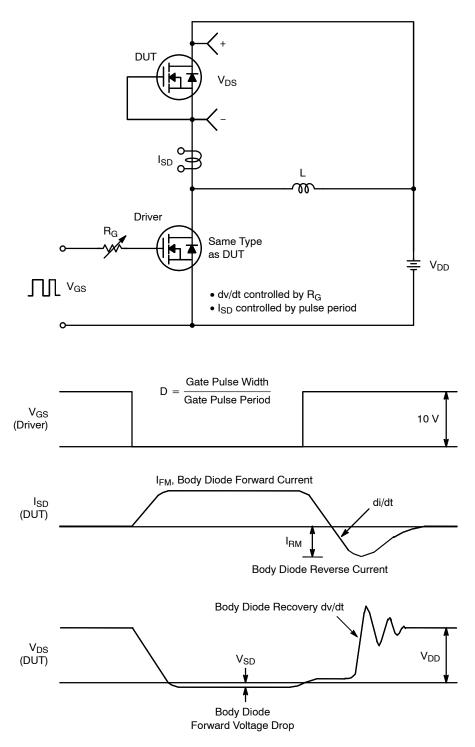
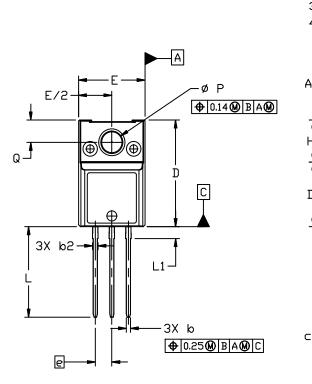


Figure 16. Peak Recovery dv/dt Test Circuit & Waveforms

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#### PACKAGE DIMENSIONS

#### TO-220 FULLPACK, 3-LEAD CASE 221BN **ISSUE O**



NDTES:

H1

D1

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 1.
- 2. CONTROLLING DIMENSION: MILLIMETERS

В

A1

A2

SEATING

- CONTOUR UNCONTROLLED IN THIS AREA. 3.
- DIMENSIONS EXCLUDE BURRS, MOLD FLASH, AND TIE BAR 4. PROTRUSIONS.

TING		MILLIMETERS				
	DIM	MIN.	NDM.	MAX.		
	Α	4.60	4.70	4.80		
	A1	2.50	2.60	2.70		
	A2	2.47	2.57	2.67		
	b	0.56	0.63	0.69		
	b2			0.90		
-NDTE 3	с	0.46	0.53	0.59		
	D	15.80	16.00	16.20		
	D1	9.58	9.68	9.78		
	Е	10.00	10.20	10.40		
	e	2.54 BSC				
	H1	6.32 REF				
	L	13.45	13.60	13.75		
	L1	1.70	1.80	1.90		
	Ρ	3.00	3.10	3.20		
	Q	3.25	3.35	3.45		

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